

# MBN1800F33F

Silicon N-channel IGBT 3300V F version

## FEATURES

- \* Soft switching behavior, low switching loss & low conduction loss :  
Soft low-injection punch-through  
Advanced Trench High conductivity IGBT.
- \* Low driving power due to low input capacitance with trench MOS gate.
- \* Low noise recovery: Ultra soft fast recovery diode.
- \* High Current rate Package.
- \* Low Rth(j-c) & low stray inductance.
- \* RoHS
- \* High thermal fatigue durability: ( $\Delta T_c=70K$ ,  $N>30,000$ cycles)

## ABSOLUTE MAXIMUM RATINGS (T<sub>c</sub>=25°C)

Item	Symbol	Unit	MBN1800F33F
Collector Emitter Voltage	V <sub>CES</sub>	V	3,300
Gate Emitter Voltage	V <sub>GES</sub>	V	±20
Collector Current	DC	I <sub>C</sub>	1,800
	1ms	I <sub>CRM</sub>	3,600
Forward Current	DC	I <sub>F</sub>	1,800
	1ms	I <sub>FRM</sub>	3,600
Junction Temperature	T <sub>j</sub>	°C	-50 ~ +150
Storage Temperature	T <sub>stg</sub>	°C	-55 ~ +150
Isolation Voltage	V <sub>ISO</sub>	V <sub>RMS</sub>	6,000(AC 1 minute)
Screw Torque	Terminals (M4/M8)	-	2/15 (1)
	Mounting (M6)	-	6 (2)

Notes: (1) Recommended Value  $1.8 \pm 0.2/15^{+0}_{-3}$  N·m (2) Recommended Value  $5.5 \pm 0.5$  N·m

## ELECTRICAL CHARACTERISTICS

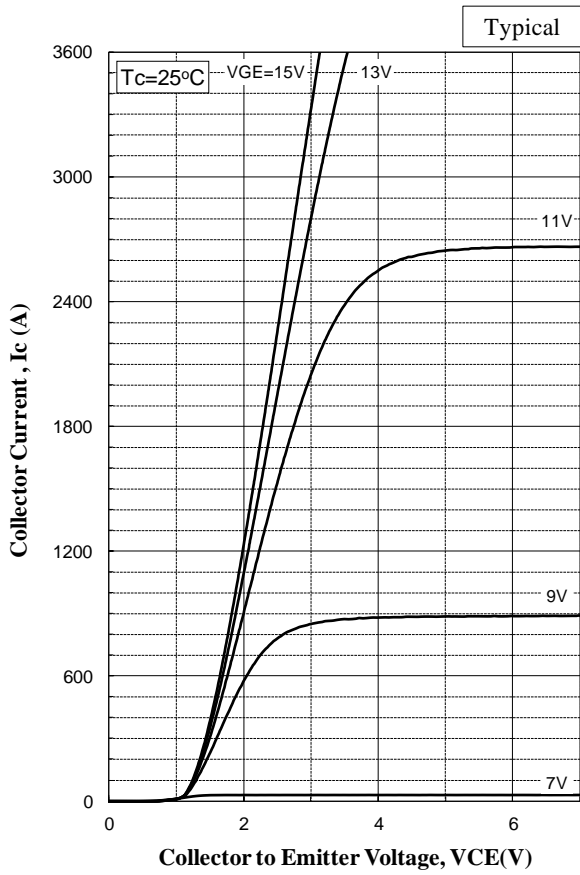
Item	Symbol	Unit	Min.	Typ.	Max.	Test Conditions
Collector Emitter Cut-Off Current	I <sub>CES</sub>	mA	-	-	0.6	V <sub>CE</sub> =3,300V, V <sub>GE</sub> =0V, T <sub>j</sub> =25°C
Gate Emitter Leakage Current	I <sub>GES</sub>	nA	-500	-	+500	V <sub>CE</sub> =3,300V, V <sub>GE</sub> =0V, T <sub>j</sub> =150°C
Collector Emitter Saturation Voltage	V <sub>CEsat</sub>	V	2.5	2.85	3.5	I <sub>C</sub> =1800A, V <sub>GE</sub> =15V, T <sub>j</sub> =25°C
Gate Emitter Threshold Voltage	V <sub>GE(th)</sub>	V	5.5	6.5	7.5	V <sub>CE</sub> =10V, I <sub>C</sub> =1800mA, T <sub>j</sub> =25°C
Input Capacitance	C <sub>ies</sub>	nF	-	132	-	V <sub>CE</sub> =10V, V <sub>GE</sub> =0V, f=100kHz, T <sub>j</sub> =25°C
Internal Gate Resistance	r <sub>g</sub>	Ω	-	1.3	-	V <sub>CE</sub> =10V, V <sub>GE</sub> =0V, f=100kHz, T <sub>j</sub> =25°C
Switching Times	Rise Time	t <sub>r</sub>	-	0.3	-	V <sub>CC</sub> =1,800V, I <sub>C</sub> =1800A
	Turn On Time	t <sub>on</sub>	-	1.1	-	L <sub>s</sub> =80nH
	Fall Time	t <sub>f</sub>	-	1.8	-	R <sub>G</sub> (on/off)=4.7Ω/5.6Ω (3)
	Turn Off Time	t <sub>off</sub>	-	4.0	-	V <sub>GE</sub> =±15V, T <sub>j</sub> =150°C
Peak Forward Voltage Drop	V <sub>F</sub>	V	2.2	2.6	2.9	I <sub>F</sub> =1800A, V <sub>GE</sub> =0V, T <sub>j</sub> =150°C
Reverse Recovery Time	t <sub>rr</sub>	μs	-	0.7	-	V <sub>CC</sub> =1,800V, I <sub>F</sub> =1800A, L <sub>s</sub> =80nH T <sub>j</sub> =150°C
Turn On Loss	E <sub>on</sub>	J/P	-	3.7	-	V <sub>CC</sub> =1,800V, I <sub>C</sub> =1800A, L <sub>s</sub> =80nH
Turn Off Loss	E <sub>off</sub>	J/P	-	3.3	-	R <sub>G</sub> (on/off)=4.7Ω/5.6Ω (3)
Reverse Recovery Loss	E <sub>rr</sub>	J/P	-	2.4	-	V <sub>GE</sub> =±15V, T <sub>j</sub> =150°C
Stray inductance module	L <sub>SCE</sub>	nH	-	7	-	
Thermal Impedance	IGBT	Rth(j-c)	-	-	0.0067	Junction to case
	FWD	Rth(j-c)	-	-	0.012	
Contact Thermal Impedance	Rth(c-f)	K/W	-	0.005	-	Case to fin
I <sup>2</sup> t value	I <sup>2</sup> t	KA <sup>2</sup> s	1000	-	-	T <sub>j,start</sub> =150°C, 10ms, V <sub>R</sub> =0V, half-sinewave

Notes: (3) R<sub>G</sub> value is a test condition value for evaluation, not recommended value.  
Please, determine the suitable R<sub>G</sub> value by measuring switching behaviors.

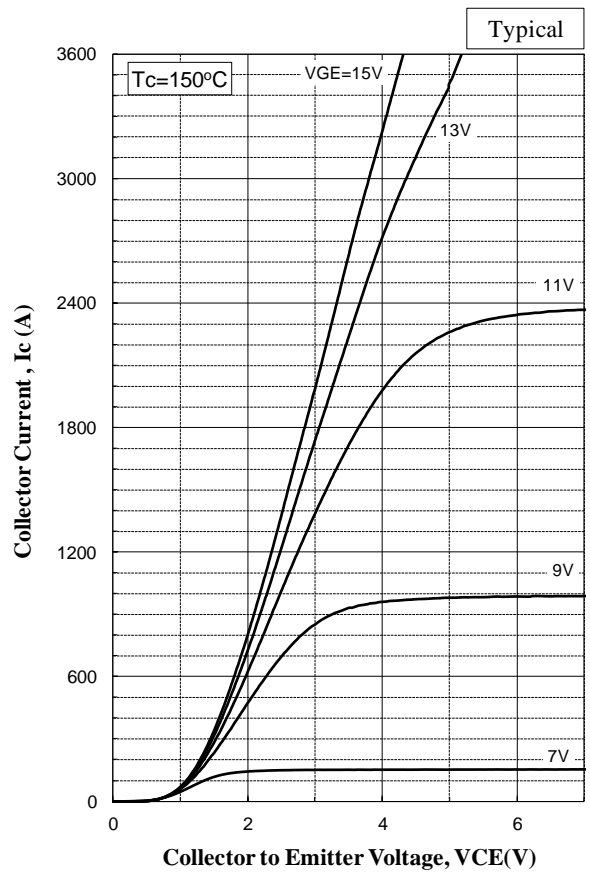
- \* Please contact our representatives at order.
- \* For improvement, specifications are subject to change without notice.
- \* For actual application, please confirm this spec sheet is the newest revision.
- \* ELECTRICAL CHARACTERISTIC values according to IEC 60747-2 IEC 60747-9

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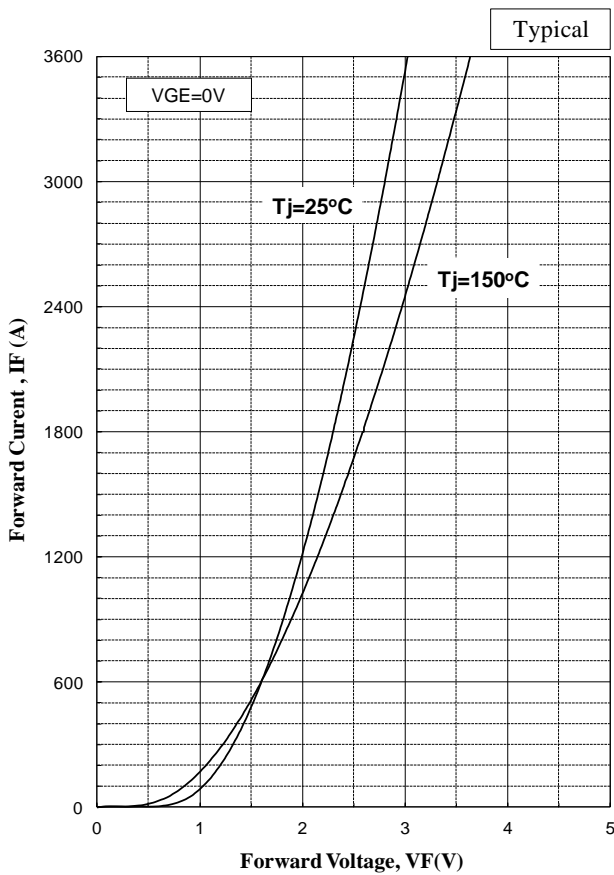
## STATIC CHARACTERISTICS



Collector Current vs. Collector to Emitter Voltage



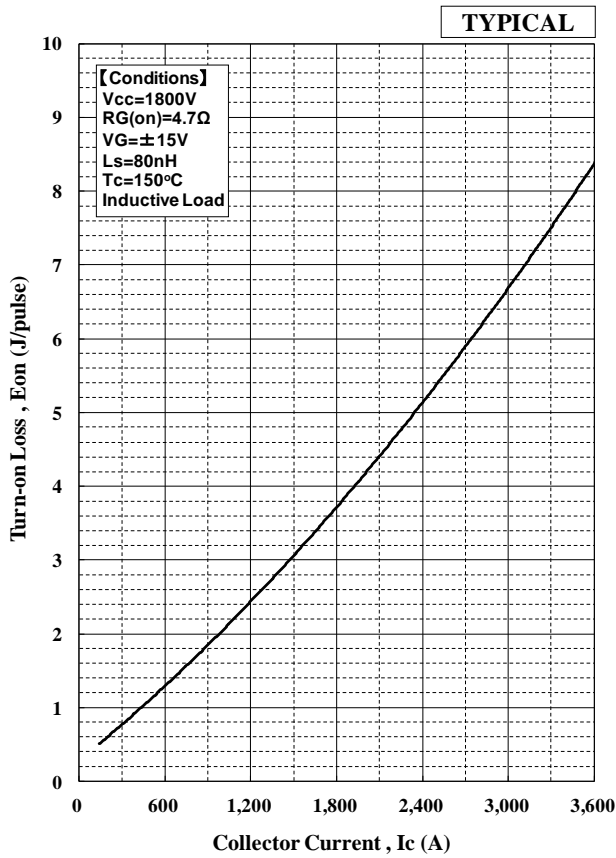
Collector Current vs. Collector to Emitter Voltage



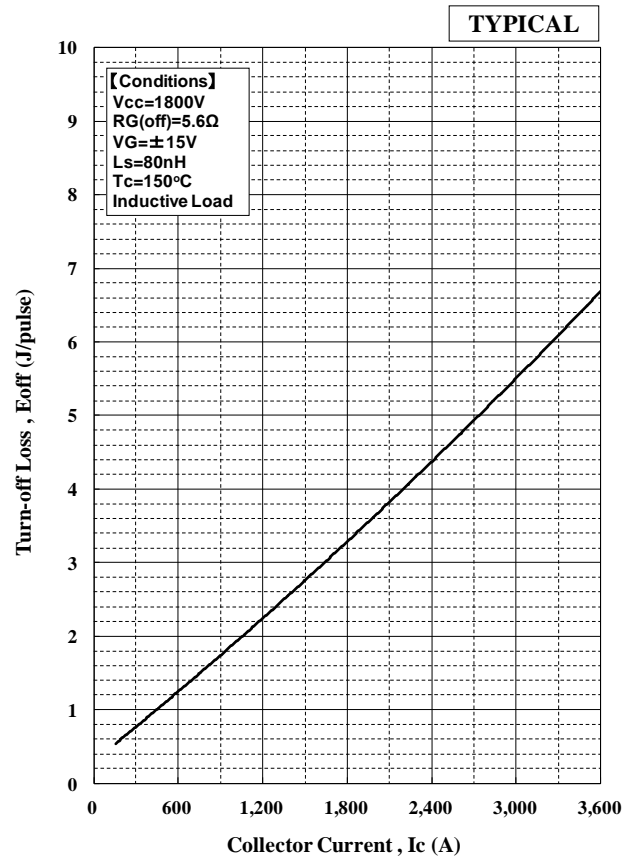
Forward Voltage of free-wheeling diode

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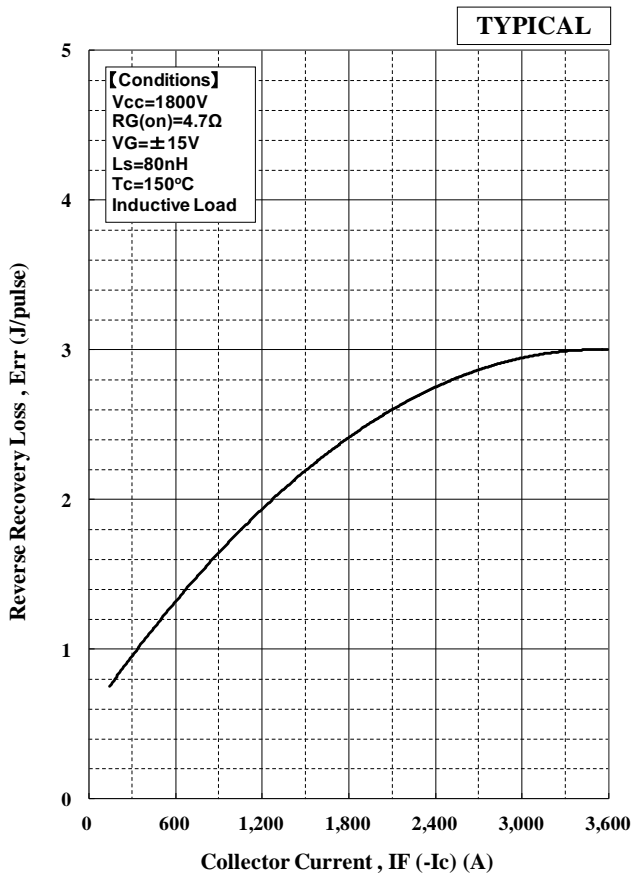
## DYNAMIC CHARACTERISTICS



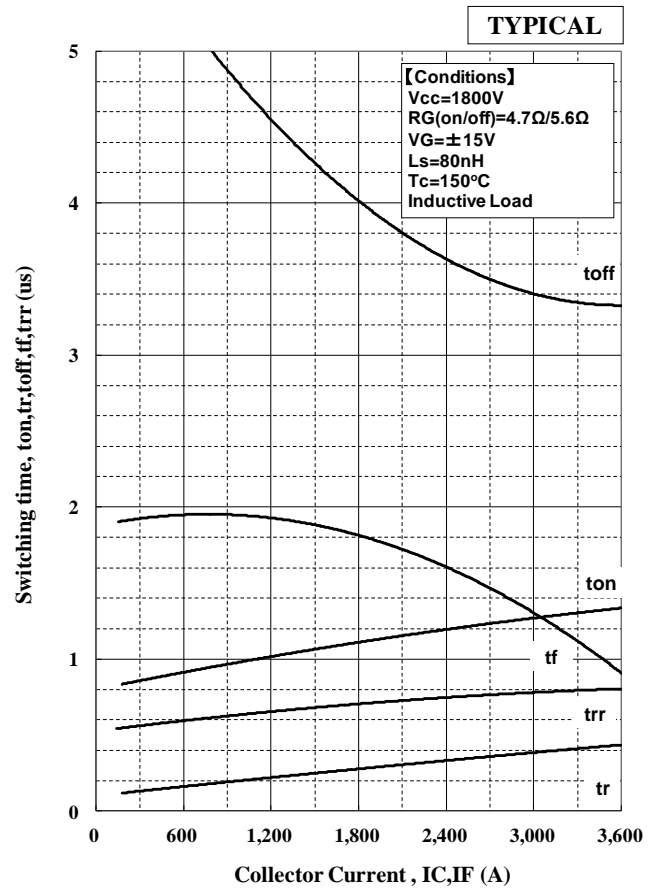
Turn-on Loss vs. Collector Current



Turn-off Loss vs. Collector Current

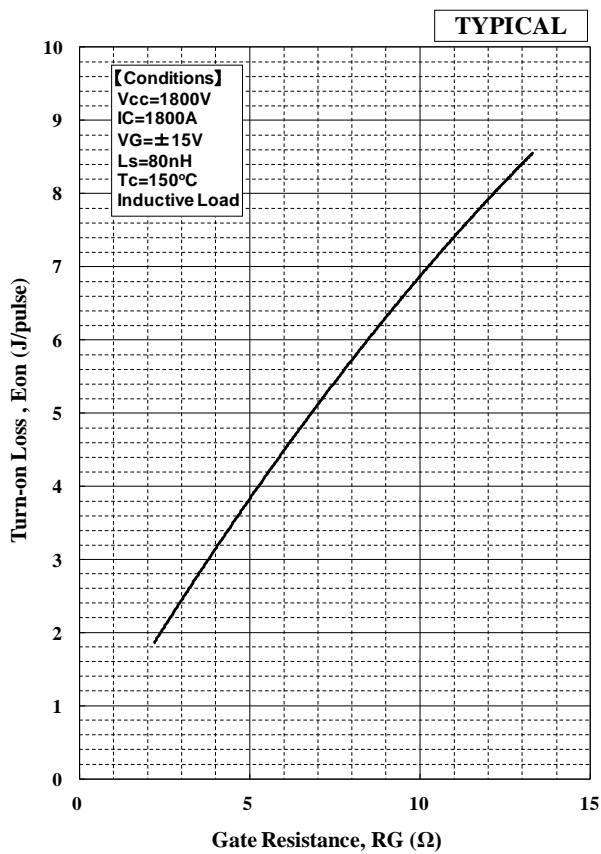


Recovery Loss vs. Collector Current

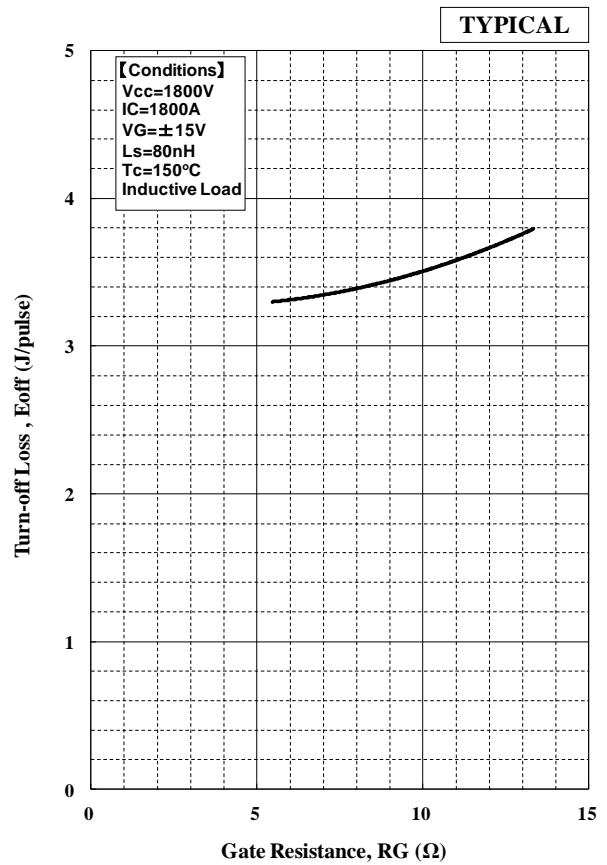


Switching time vs. Collector Current

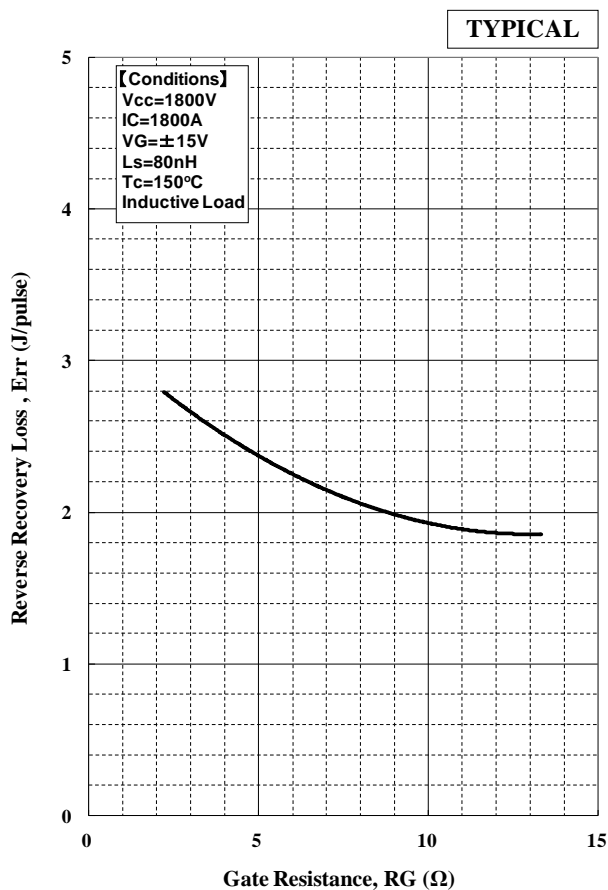
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Turn-on Loss vs. Gate Resistance



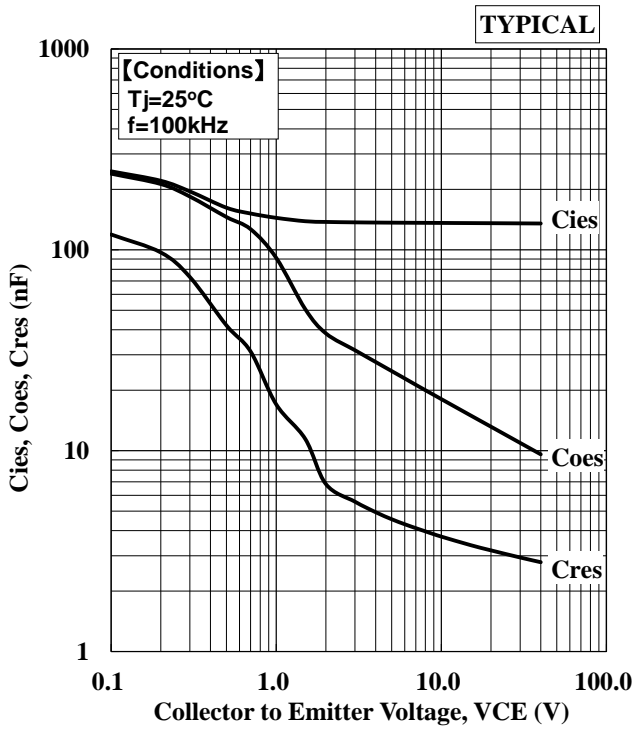
Turn-off Loss vs. Gate Resistance



Recovery Loss vs. Gate Resistance

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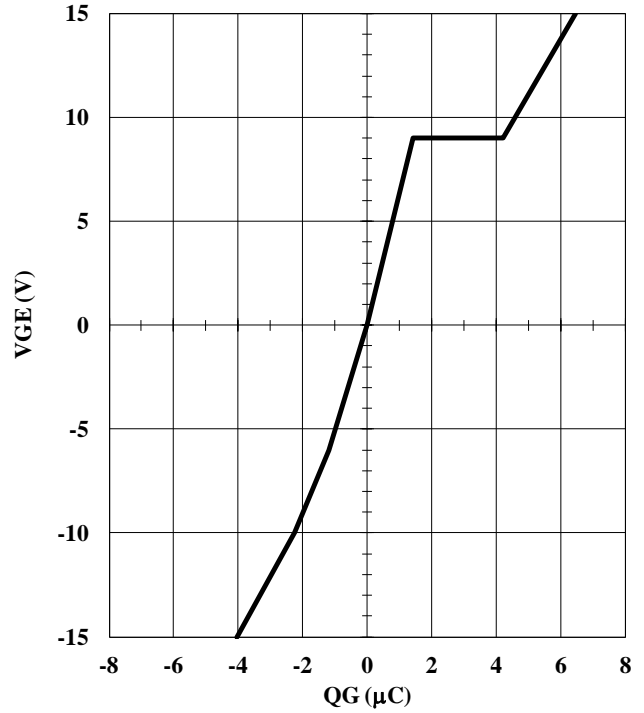
## Capacitance vs. Collector to Emitter Voltage



Capacitance vs. Collector to Emitter Voltage

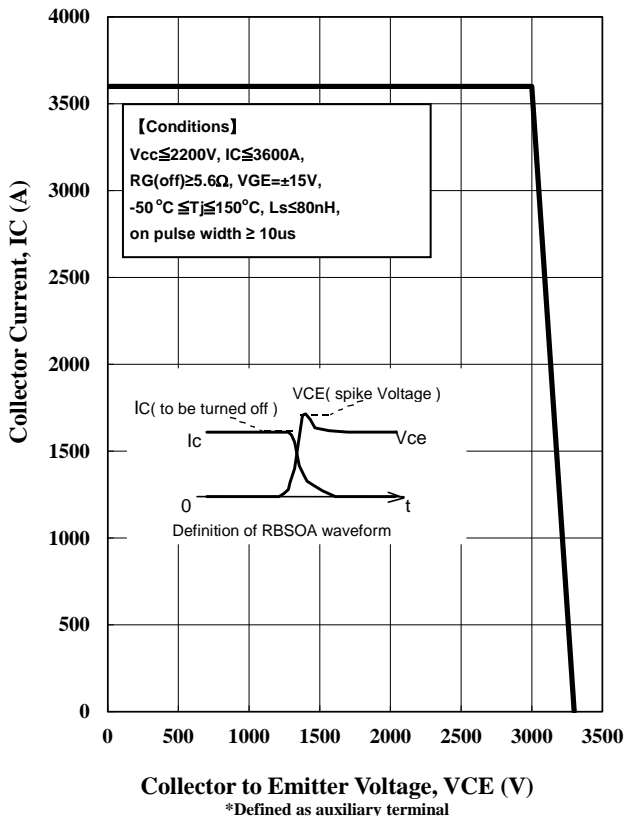
## QG-VGE CURVE

Conditions:  $L_s = 80\text{nH}$ ,  $V_{CC} = 1800\text{V}$ ,  
 $I_C = 1800\text{A}$ ,  $V_{GE} = \pm 15\text{V}$ ,  $T_j = 25^\circ\text{C}$  **TYPICAL**

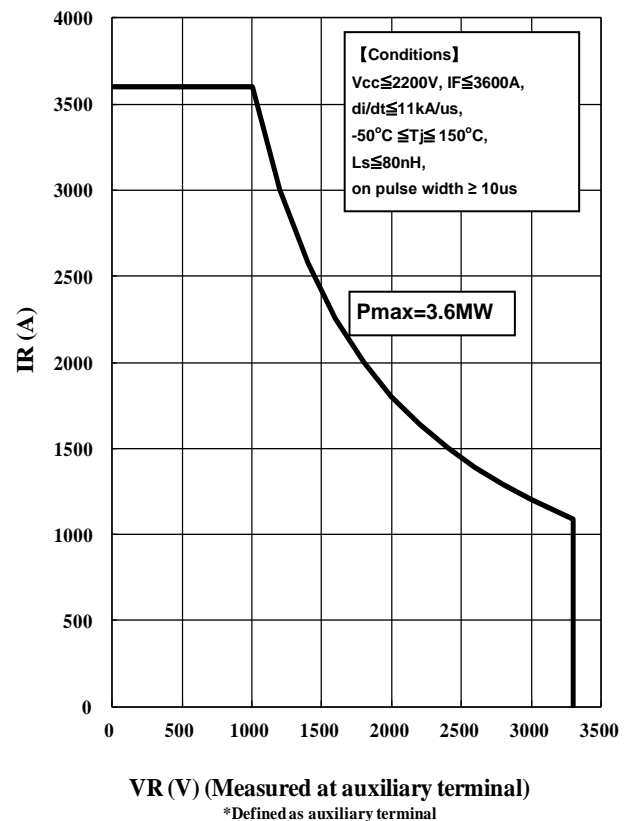


QG-VGE curve

## Safe Operating Area



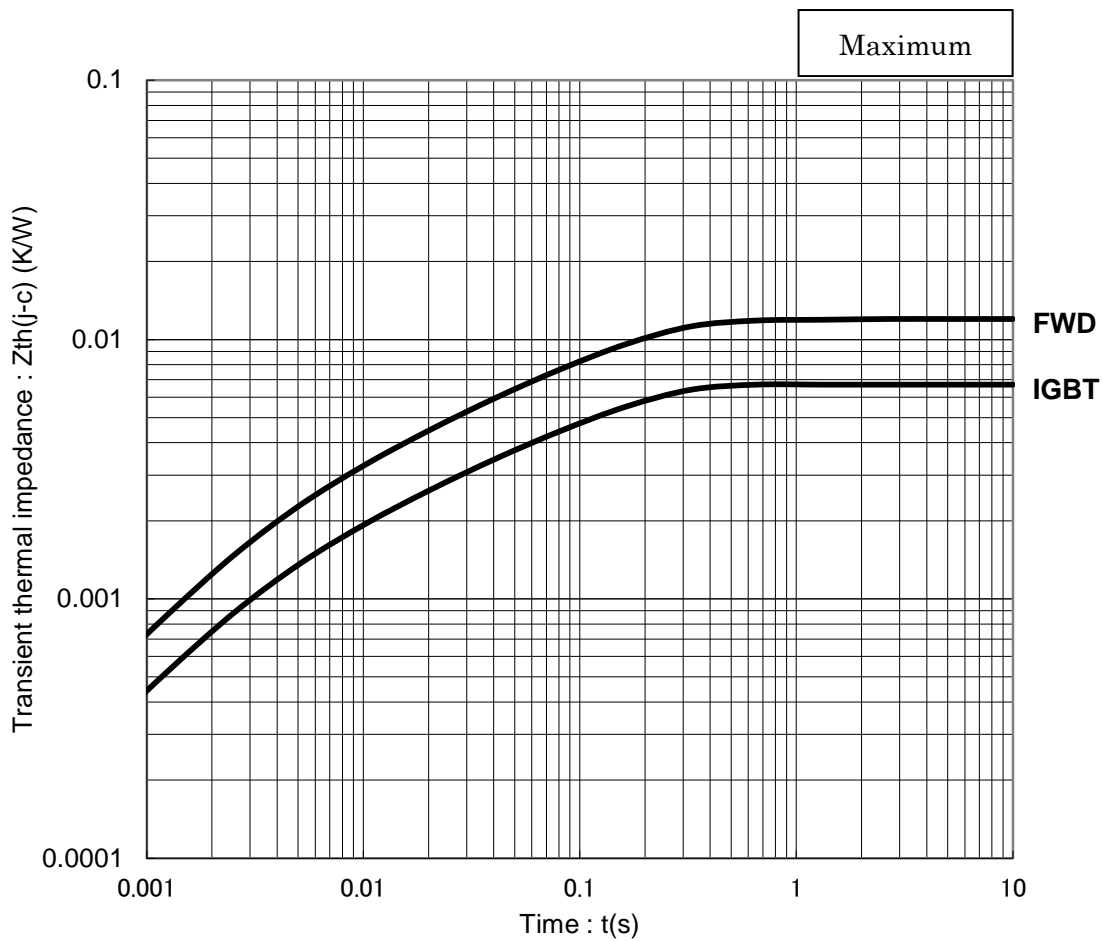
Reverse bias safe operation area(RBSOA)



Reverse recovery safe operation area(RRSOA)

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## TRANSIENT THERMAL IMPEDANCE



Transient Thermal Impedance Curve

### Curve approximation model

$$(\sum Z_{th}[n] * (1 - \exp(-t/\tau_{th}[n])))$$

n	1	2	3	4	Unit
$\tau_{th}[n]$	0.003	0.03	0.1	0.3	sec
$Z_{th}[n,IGBT]$	1.36E-03	7.88E-04	4.11E-03	4.49E-04	K/W
$Z_{th}[n,Diode]$	2.26E-03	1.62E-03	6.71E-03	1.41E-03	K/W

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## OUTLINE DRAWINGS

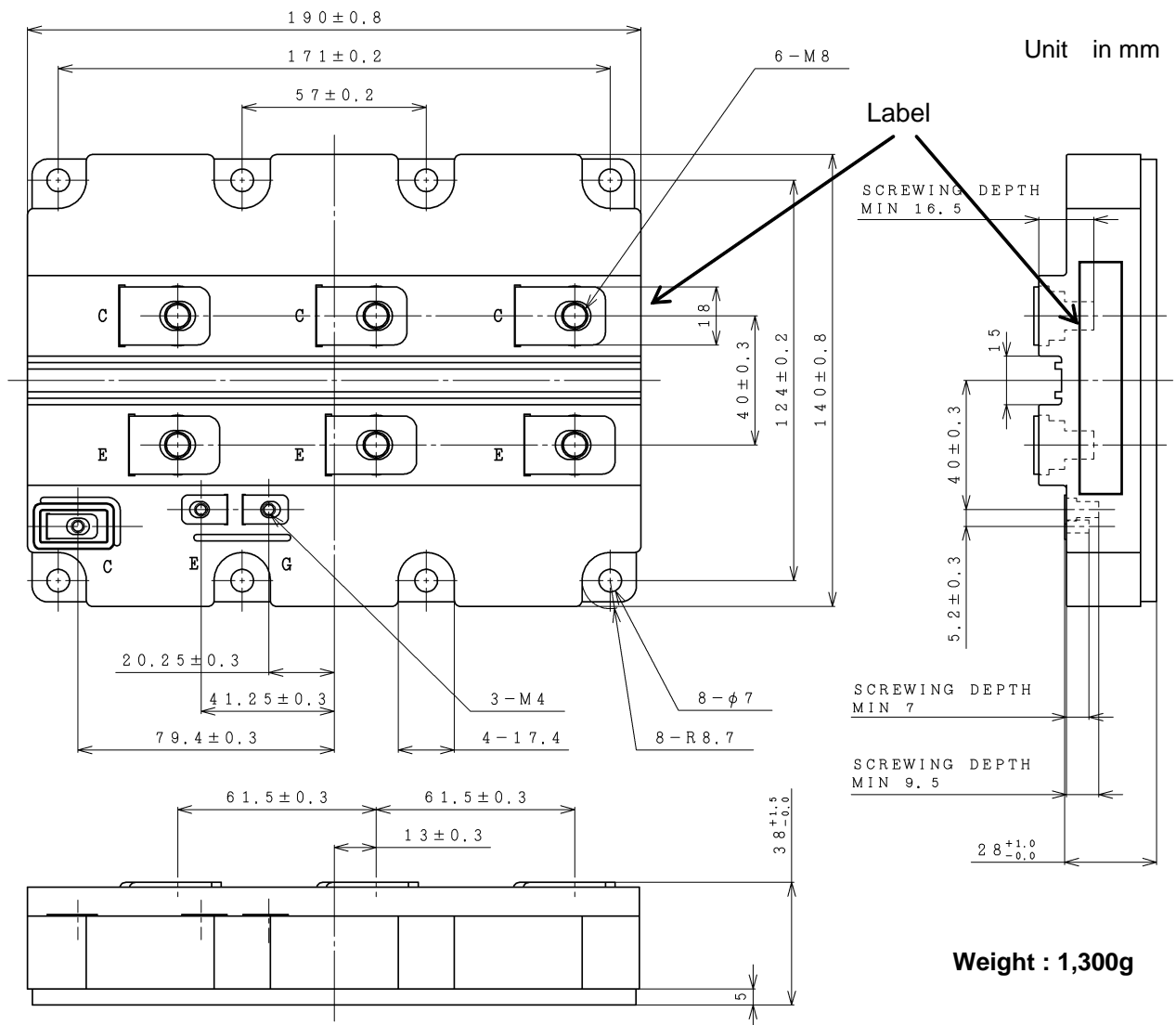


Fig.1 Outline Drawings

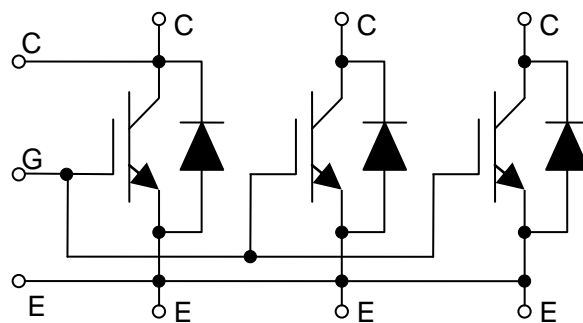


Fig.2 Circuit diagram

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## HITACHI POWER SEMICONDUCTORS

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